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Patent Application

Inventor(s): C.W. Jones

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Title: METHOD AND APPARATUS FOR GENERATING AN OPTIMAL TEST PATTERN FOR SEQUENCE DETECTION

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U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
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Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation Yes	Translation No
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Other Documents

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/JPT/	I	Manoj Franklin and Kewal K. Saluja; EMBEDDED RAM TESTING; 1995 IEEE; pp.29-33
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Examiner	Date Considered
/John P Trimmings/	05/10/2010

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.